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National Semiconductor

54ACTQ16540
16-Bit Inverting Buffer/Line Driver with TRI-STATE® Outputs

General Description

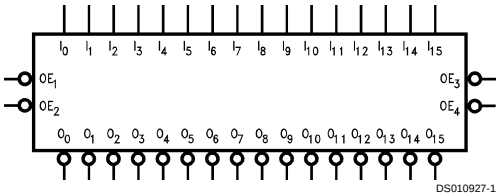
The 'ACTQ16540 contains sixteen inverting buffers with TRI-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/receiver. The device is byte controlled. Each byte has separate TRI-STATE control inputs which can be shorted together for full 16-bit operation.

The 'ACTQ16540 utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series® features GTO® output control for superior performance.

Features

- Utilizes NSC FACT Quiet Series technology
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Separate control logic for each byte
- 16-bit version of the 'ACTQ540
- Outputs source/sink 24 mA
- Additional specs for multiple output switching

Logic Symbol



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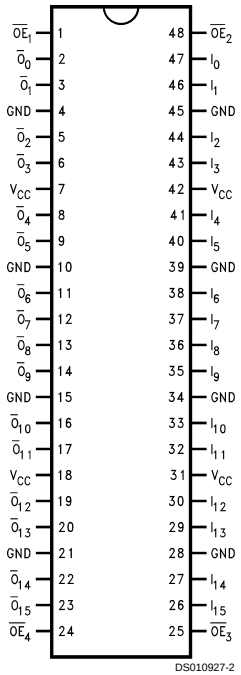
Pin Description

Pin Names	Description
$\overline{OE}_n$	Output Enable Input (Active Low)
I_0–I_{15}	Inputs
$\overline{O}_0$–$\overline{O}_{15}$	Outputs

Connection Diagram

Pin Assignment for CERPAK



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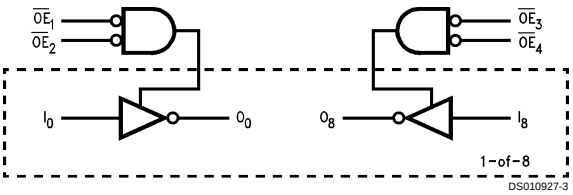
Functional Description

The 'ACTQ16540 contains sixteen inverting buffers with TRI-STATE standard outputs. The device is byte controlled with each byte functioning identically, but independent of the other. The control pins may be shorted together to obtain full 16-bit operation. The TRI-STATE outputs are controlled by an Output Enable ($\overline{OE}_n$) input for each byte. When $\overline{OE}_n$ is LOW, the outputs are in 2-state mode. When $\overline{OE}_n$ is HIGH, the outputs are in the high impedance mode, but this does not interfere with entering new data into the inputs.

Logic Diagram



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Truth Table

Inputs			Outputs
$\overline{OE}_1$	$\overline{OE}_2$	I_0–I_7	$\overline{O}_0$–$\overline{O}_7$
L	L	H	L
H	X	X	Z
X	H	X	Z
L	L	L	H

Inputs			Outputs
$\overline{OE}_3$	$\overline{OE}_4$	I_8–I_{15}	$\overline{O}_8$–$\overline{O}_{15}$
L	L	H	L
H	X	X	Z
X	H	X	Z
L	L	L	H

H = High Voltage Level
L = Low Voltage Level
X = Immaterial
Z = High Impedance

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 mA
V_I = V_{CC} + 0.5V	+20 mA
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source/Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin	±50 mA
Junction Temperature	
CDIP	+175˚C
Storage Temperature	−65˚C to +150˚C

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACTQ	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A):	
54ACTQ	−55˚C to +125˚C
Minimum Input Edge Rate (dV/dt)	
'ACTQ Devices	125 mV/ns
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics for 'ACTQ Family Devices

Symbol	Parameter	V_{CC} (V)	54ACTQ T_A = −55˚C to +125˚C Guaranteed Limits	Units	Conditions
V_{IH}	Minimum High Input Voltage	4.5 5.5	2.0 2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{IL}	Maximum Low Input Voltage	4.5 5.5	0.8 0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{OH}	Minimum High Output Voltage	4.5 5.5	4.4 5.4	V	I_{OUT} = −50 µA
					(Note 2) V_{IN} = V_{IL} or V_{IH}
		4.5 5.5	3.70 4.70	V	I_{OH} = −24 mA I_{OH} = −24 mA
V_{OL}	Maximum Low Output Voltage	4.5 5.5	0.1 0.1	V	I_{OUT} = 50 µA
					(Note 2) V_{IN} = V_{IL} or V_{IH}
		4.5 5.5	0.50 0.50	V	I_{OL} = 24 mA I_{OL} = 24 mA
I_{OZ}	Maximum TRI-STATE Leakage Current	5.5	±10.0	µA	V_I = V_{IL}, V_{IH} V_O = V_{CC}, GND
I_{IN}	Maximum Input Leakage Current	5.5	±1.0	µA	V_I = V_{CC}, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	1.6	mA	V_I = V_{CC} − 2.1V
I_{CC}	Max Quiescent Supply Current	5.5	160.0	µA	V_{IN} = V_{CC} or GND
I_{OLD}	Minimum Dynamic Output Current (Note 3)	5.5	50	mA	V_{OLD} = 1.65V Max
I_{OHD}			-50	mA	V_{OHD} = 3.85V Min

DC Electrical Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	54ACTQ $T_A = -55^\circ C$ to $+125^\circ C$ Guaranteed Limits	Units	Conditions
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	0.8	V	(Note 4)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	-0.8	V	(Note 4)

Note 2: All outputs loaded; thresholds associated with output under test.

Note 3: Maximum test duration 2.0 ms; one output loaded at a time.

Note 4: Maximum number of outputs that can switch simultaneously is n. (n − 1) outputs are switched HIGH and one output held HIGH.

AC Electrical Characteristics

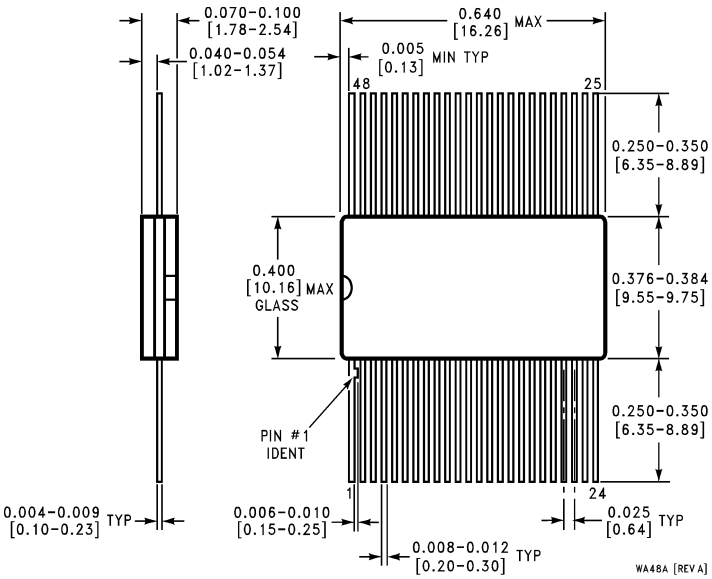
Symbol	Parameter	V_{CC} (V) (Note 5)	54ACTQ $T_A = -55^\circ C$ to $+125^\circ C$ $C_L = 50$ pF		Units
			Min	Max	
t_{PLH}, t_{PHL}	Propagation Delay Data to Output	5.0	3.0 3.0	9.0 9.5	ns
t_{PZH}, t_{PZL}	Output Enable Time	5.0	3.0 3.0	10.0 11.0	ns
t_{PHZ}, t_{PLZ}	Output Disable Time	5.0	2.5 2.5	10.5 10.5	ns

Note 5: Voltage Range 5.0 is 5.0V ±0.5V.

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Pin Capacitance	4.5	pF	V_{CC} = 5.0V
C_{PD}	Power Dissipation	30	pF	V_{CC} = 5.0V

Physical Dimensions inches (millimeters) unless otherwise noted



48-Lead CERPAK (F)
NS Package Number WA48A

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National Semiconductor Corporation
Americas
Tel: 1-800-272-9959
Fax: 1-800-737-7018
Email: support@nsc.com

www.national.com

National Semiconductor Europe
Fax: +49 (0) 1 80-530 85 86
Email: europe.support@nsc.com
Deutsch Tel: +49 (0) 1 80-530 85 85
English Tel: +49 (0) 1 80-532 78 32
Français Tel: +49 (0) 1 80-532 93 58
Italiano Tel: +49 (0) 1 80-534 16 80

National Semiconductor Asia Pacific Customer Response Group
Tel: 65-2544466
Fax: 65-2504466
Email: sea.support@nsc.com

National Semiconductor Japan Ltd.
Tel: 81-3-5620-6175
Fax: 81-3-5620-6179